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1.  **A transparent online memory test for simultaneous detection of functional faults and soft errors in memories**
    Thaller, K.; Steininger, A.;
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    Volume 52, Issue 4, Dec. 2003 Page(s):413 - 422

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2.  **A highly-efficient transparent online memory test**
    Thaller, K.;
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3.  **Predicting the number of fatal soft errors in Los Alamos national laboratory's ASC Q supercomputer**
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    Volume 5, Issue 3, Sept. 2005 Page(s):329 - 335

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1. **A highly-efficient transparent online memory test**
Thaller, K.;
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2. **Achieving fault secureness in parity prediction arithmetic operators: general conditions and implementations**
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